

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
(Not for submission under 37 CFR 1.99)

Application Number	10781985
Filing Date	2004-02-20
First Named Inventor	Uri MAHLAB
Art Unit	2613
Examiner Name	David S. KIM
Attorney Docket Number	MAHLAB-8

/DSK/	12	Fiber Optic Test and Measurement, Derickson, Dennis. Book, 1998, Prentice Hall, USA ., Section 1.12.5	<input type="checkbox"/>
-------	----	---	--------------------------

If you wish to add additional non-patent literature document citation information please click the Add button

EXAMINER SIGNATURE

Examiner Signature	/David S. Kim/	Date Considered	12/18/2007
--------------------	----------------	-----------------	------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through a citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ See Kind Codes of USPTO Patent Documents at www.USPTO.GOV or MPEP 901.04. ² Enter office that issued the document, by the two-letter code (WIPO Standard ST.3). ³ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁴ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁵ Applicant is to place a check mark here if English language translation is attached.

Application Number	10/781,985
Filing Date	February 20, 2004
First Named Inventor	Uri MAHLAB
Group Art Unit	4645 2613
Examiner Name	David S. KIM
Attorney Docket Number	MAHLAB-8

Examiner. Signature	/David S. Kim/	Date Considered	12/18/2007
------------------------	----------------	--------------------	------------

*** EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 801.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Complete If Known

Sheet	Attorney Docket Number	MAHLAB-8	2	Application Number	10/781,985
				Filing Date	February 20, 2004
				First Named Inventor	Uri MAHLAB
				Group Art Unit	4845 2613
				Examiner Name	David S. KIM
				Attorney Docket Number	MAHLAB-8

NON PATENT LITERATURE DOCUMENTS / OTHER INFORMATION

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²
/DSK/	AL	G. Rossi et al. "Optical Performance Monitoring in Reconfigurable WDM Optical Networks Using Subcarrier Multiplexing", Journal of Lightwave Technology, Vol. 18, No. 12, December 2000.	
	AM	A. Sano et al. "Adaptive Dispersion Equalization by Monitoring Relative Phase Shift Between Spacing-Fixed WDM Signals", Journal of Lightwave Technology, Vol. 19 No. 3, March 2001.	
	AN	A. E. Willner et al. "Tunable Compensation of Channel Degrading Effects Using Nonlinearly Chirped Passive Fiber Bragg Gratings", IEEE Journal of Selected Topics in Quantum Electronics, Vol. 5, No. 5, September/October 1999.	
	AO	S. Wielandy et al. "Real-time measurement of accumulated chromatic dispersion for automatic dispersion compensation", Electronic Letters, Vol. 38, No. 20, September 26, 2002.	

Examiner
Signature

/David S. Kim/

Date
Considered

12/18/2007

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Not for submission under 37 CFR 1.99)

Application Number	10781985
Filing Date	2004-02-20
First Named Inventor	Uri MAHLAB
Art Unit	2613
Examiner Name	David S. KIM
Attorney Docket Number	MAHLAB-8

U.S. PATENTS

Examiner Initial*	Cite No	Patent Number	Kind Code ¹	Issue Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines where Relevant Passages or Relevant Figures Appear
	1					

If you wish to add additional U.S. Patent citation information please click the Add button.

U.S. PATENT APPLICATION PUBLICATIONS

Examiner Initial*	Cite No	Publication Number	Kind Code ¹	Publication Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines where Relevant Passages or Relevant Figures Appear
	1					

If you wish to add additional U.S. Published Application citation information please click the Add button.

FOREIGN PATENT DOCUMENTS

Examiner Initial*	Cite No	Foreign Document Number ³	Country Code ²ⁱ	Kind Code ⁴	Publication Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines where Relevant Passages or Relevant Figures Appear	T ⁵
/DSK/	1	20010001620	KR		2001-01-05	Kim Sang Ho et al.	Abstract only	<input type="checkbox"/>

If you wish to add additional Foreign Patent Document citation information please click the Add button

NON-PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc), date, pages(s), volume-issue number(s), publisher, city and/or country where published.	T ⁵

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
(Not for submission under 37 CFR 1.99)

Application Number	10781985
Filing Date	2004-02-20
First Named Inventor	Uri MAHLAB
Art Unit	2613
Examiner Name	David S. KIM
Attorney Docket Number	MAHLAB-8

/DSK/	1	Simple Measurement Of Fiber Dispersion And Of Chirp Parameter Of Intensity Modulated Light Emitter. F. Devaux, Y. Sorel And J.F.Kerdiles. Journal of Lightwave Technology, Vol.11, No.12 December 1993.	<input type="checkbox"/>
	2	Direct Measurement Of Chirped Fundamental And Stimulated Raman Radiation In Fibers. Gomes, A. S. L. (Imperial Coll, London, Engl); Da Silva, V. L.; Taylor, J. R., Optical Soc of America, 1987, p 82	<input type="checkbox"/>
	3	Variation of frequency chirp with wavelength in an InGaAsP/InP multiple-quantum-well (MQW) waveguide electroabsorption modulator, M.S. Whalen; T.H. Wood; B.I. Miller; U. Koren; C.A. Burrus; G. Raybon, Photonics Technology Letters, IEEE, Volume: 3. Issue: 5 May 1991, Page(s): 451-452	<input type="checkbox"/>
	4	Wideband chirp measurement technique for high bit rate sources. R.A. Sanders, J.P. King, and I. Hardcastle. IEEE 1994. Electronics Letters Online No:19940917, 20 June 1994.	<input type="checkbox"/>
	5	Time-resolved measurement of dynamic frequency chirp due to electrostriction mechanism in optical fibers, D. Le Quang; Y. Jaouen; M. Zimmerli; P. Gallion; J.B. Thomine, Photonics Technology Letters, IEEE, Volume: 8 Issue: 3 March 1996, Page(s): 414-416	<input type="checkbox"/>
	6	Time-resolved frequency chirp measurement using a silicon-wafer etalon, S. Tammela; H. Ludvigsen; T. Kajava; M. Kaivola, Photonics Technology Letters, IEEE, Volume: 9 Issue: 4 April 1997, Page(s): 475-477	<input type="checkbox"/>
	7	http://lib.tkk.fi/Diss/2002/isbn9512259869/isbn9512259869.pdf - Dispersion measurements of fiber-optic components and applications of a novel tunable filter for optical communications. Tapio Niemi. Helsinki University of Technology. Department of ECE. June 14, 2002.	<input type="checkbox"/>
	8	"Device for frequency chirp measurements of optical transmitters in real time" Tapio Niemi et al .Review of scientific instruments, Vol 73, no.3; March 2002	<input type="checkbox"/>
	9	Chirp Measurement of Multimode Q-Switched Laser Diode Pulses by Use of a Streak Camera and a Grating Monochromator, A. Bresson, N. Stelmakh, J. -M. Lourtioz, A. Shen, and C. Froehly, Appl. Opt. 37, 1022-1025 (1998)	<input type="checkbox"/>
	10	https://www.cerias.purdue.edu/tools_and_resources/bibtex_archive/archive/2000-26.pdf DIRECT SPACE-TO-TIME PULSE SHAPING FOR ULTRAFast OPTICAL WAVEFORM GENERATION. - Daniel Leaird. A thesis submitted to the Faculty of Purdue University. December 2000	<input type="checkbox"/>
↓	11	http://www.tek.com/M Measurement/cgi-bin/framed.pl?Document=/Measurement/Products/press/optical/&FrameSet=optical - Tektronix Makes Strong Push into DWDM Market with Portfolio of Photonics Network Measurement Systems - Q7606 Chirp Test Instrument.	<input type="checkbox"/>